

## 4 x 4 REGISTER FILE

### DESCRIPTION

The T54LS170/T74LS170 is a high speed, low-power 4 x 4 Register File organized as four word by four bits. Separate read and write inputs, both address and enable, allow simultaneous read and write operation.

Open collector outputs make it possible, to connect up to 128 outputs in a wired-AND configuration to increase the word capacity up to 512 words. Any number of these devices can be operated in parallel to generate an n-bit length.

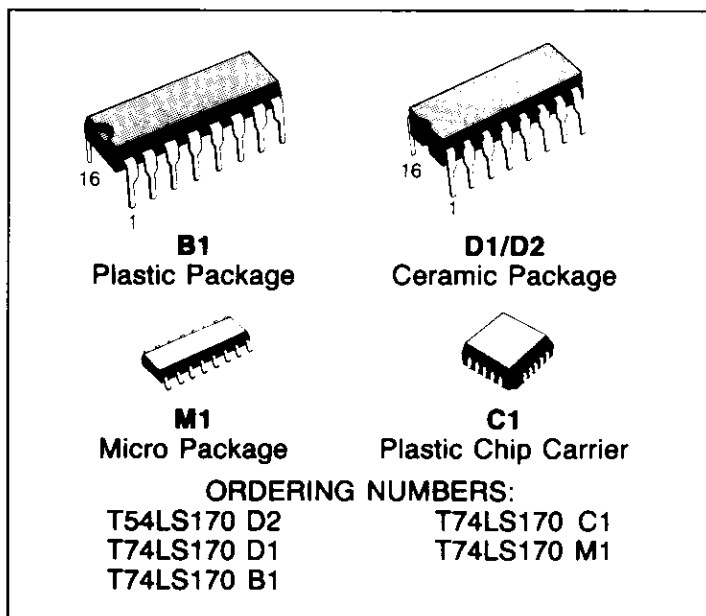
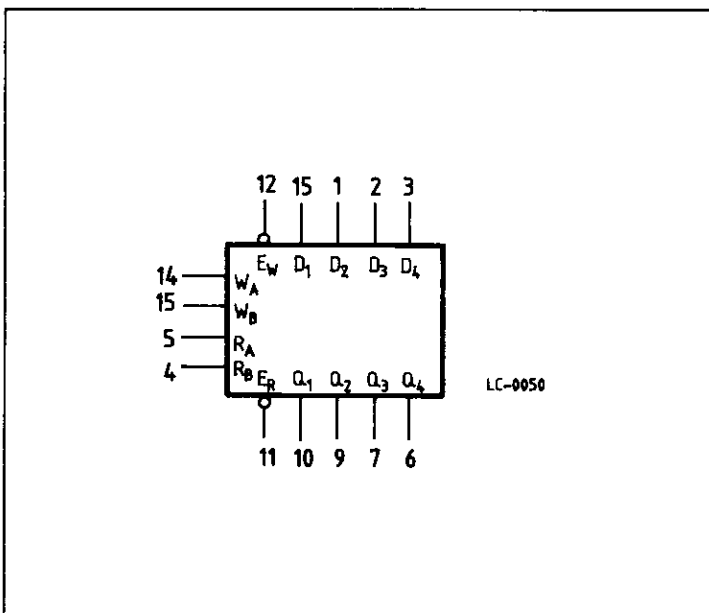
The T54LS670/T74LS670 provides a similar function to this device but it features 3-state outputs.

- SIMULTANEOUS READ/WRITE OPERATION
- EXPANDABLE TO 512 WORDS OF n-BIT
- TYPICAL ACCESS TIME OF 20 ns
- LOW LEAKAGE OPEN-COLLECTOR OUTPUTS FOR EXPANSION
- TYPICAL POWER DISSIPATION OF 125 mW
- INPUT CLAMP DIODES LIMIT HIGH SPEED TERMINATION EFFECTS
- FULLY COMPATIBLE

### PIN NAMES

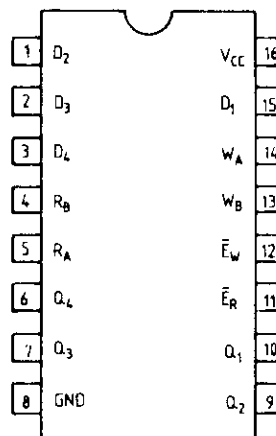
D <sub>1</sub> -D <sub>4</sub>	Data Inputs
W <sub>A</sub> -W <sub>B</sub>	Write Address Inputs
$\bar{E}_W$	Write Enable (Active LOW) Input
R <sub>A</sub> -R <sub>B</sub>	Read Address Inputs
$\bar{E}_R$	Read Enable (Active LOW) Input
Q <sub>1</sub> -Q <sub>4</sub>	Outputs

### LOGIC DIAGRAM



### PIN CONNECTION (top view)

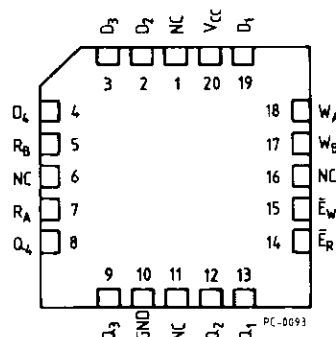
#### DUAL IN LINE



PC-0131

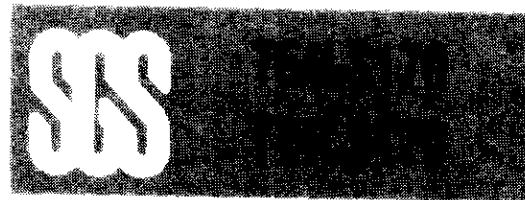
\* Open Collector Outputs

#### CHIP CARRIER



PC-0093

NC = No Internal Connection



## WRITE/READ TRUTH TABLES

WRITE TRUTH TABLE (SEE NOTES A, B, AND C)

WRITE INPUTS			WORD			
W <sub>B</sub>	W <sub>A</sub>	$\bar{E}_W$	0	1	2	3
L	L	L	Q = D	Q <sub>0</sub>	Q <sub>0</sub>	Q <sub>0</sub>
L	H	L	Q <sub>0</sub>	Q = D	Q <sub>0</sub>	Q <sub>0</sub>
H	L	L	Q <sub>0</sub>	Q <sub>0</sub>	Q = D	Q <sub>0</sub>
H	H	L	Q <sub>0</sub>	Q <sub>0</sub>	Q <sub>0</sub>	Q = D
X	X	H	Q <sub>0</sub>	Q <sub>0</sub>	Q <sub>0</sub>	Q <sub>0</sub>

READ TRUTH TABLE (SEE NOTES A AND B)

READ INPUTS			OUTPUTS			
R <sub>B</sub>	R <sub>A</sub>	$\bar{E}_R$	Q <sub>1</sub>	Q <sub>2</sub>	Q <sub>3</sub>	Q <sub>4</sub>
L	L	L	W0B1	W0B2	W0B3	W0B4
L	H	L	W1B1	W1B2	W1B3	W1B4
H	L	L	W2B1	W2B2	W2B3	W2B4
H	H	L	W3B1	W3B2	W3B3	W3B4
X	X	H	H	H	H	H

NOTES: A. H = HIGH Level, L = LOW Level, X = Don't Care

B. (Q = D) = The four selected internal flip-flop outputs will assume the states applied to the four external data inputs.

C. Q<sub>0</sub> = The level of Q before the indicated input conditions were established.

D. W0B1 = The first bit of word 0. etc.

## ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	-0.5 to 7	V
V <sub>I</sub>	Input Voltage, Applied to Input	-0.5 to 15	V
V <sub>O</sub>	Output Voltage, Applied to Output	-0.5 to 10	V
I <sub>I</sub>	Input Current, Into Inputs	-0.5 to 50	mA
I <sub>O</sub>	Output Current, Into Outputs	50	mA

Stresses in excess of those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions in excess of those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## GUARANTEED OPERATING RANGES

Part Numbers	Supply Voltage			Temperature
	Min	Typ	Max	
T54LS170D2	4.5 V	5.0 V	5.5 V	-55°C to +125°C
T74LS170XX	4.75 V	5.0 V	5.25 V	0°C to +70°C

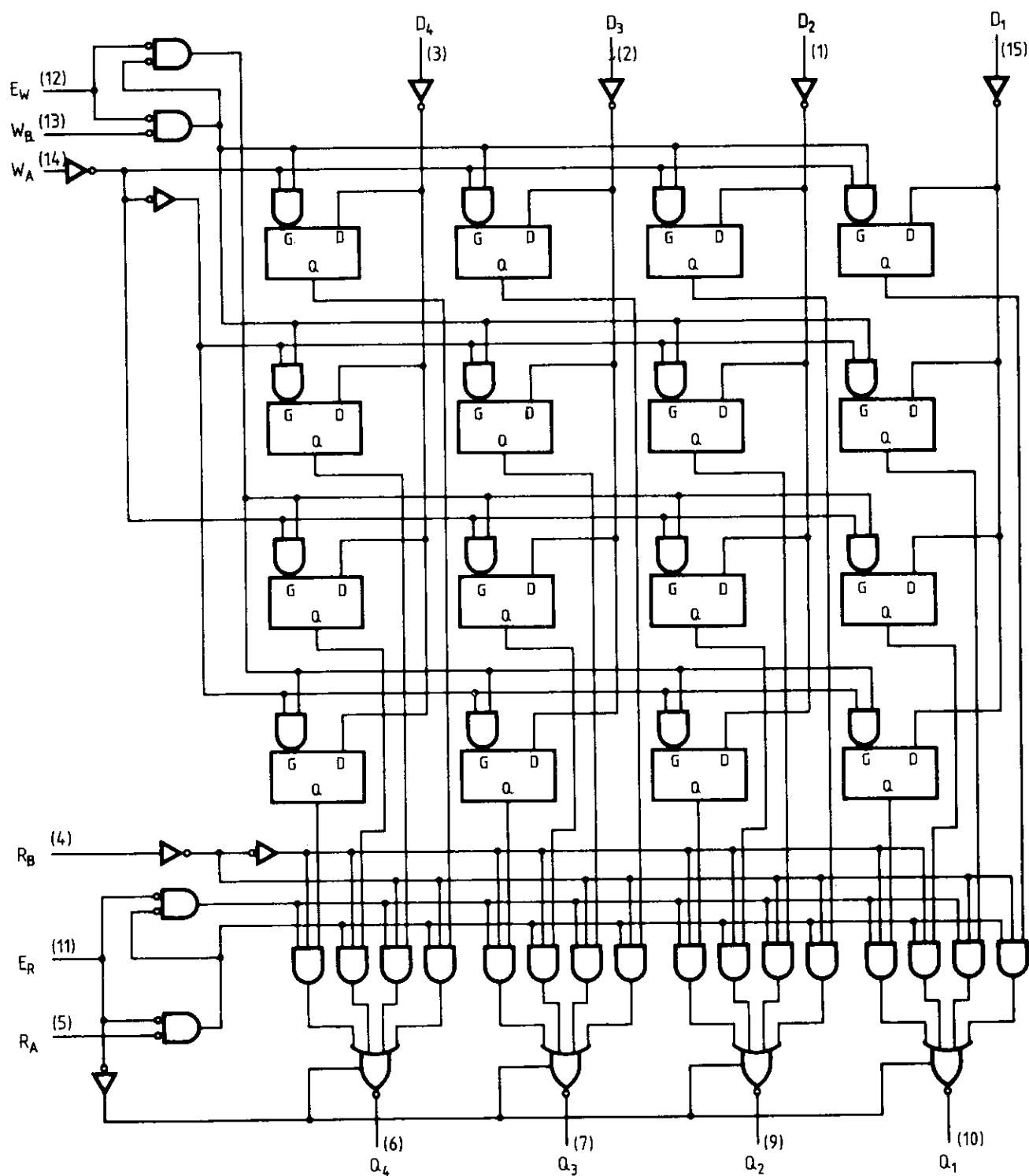
XX = package type.



T54LS170

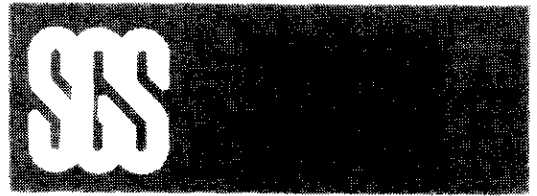
T74LS170

## LOGIC SYMBOL



LC-0143

V<sub>CC</sub> = Pin 16  
GND = Pin 8  
( ) = Pin numbers



## DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

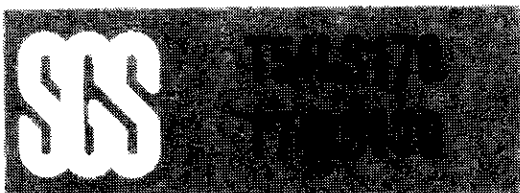
Symbol	Parameter		Limits			Test Conditions (Note 1)	Units
			Min.	Typ.	Max.		
$V_{IH}$	Input HIGH Voltage		2.0			Guaranteed input HIGH Voltage for all Inputs	V
$V_{IL}$	Input LOW Voltage	54			0.7	Guaranteed input LOW Voltage for all Inputs	V
		74			0.8		
$V_{CD}$	Input Clamp Diode Voltage			-0.65	-1.5	$V_{CC} = \text{MIN}, I_{IN} = -18\text{mA}$	V
$I_{OH}$	Output HIGH Current				20	$V_{OH} = 5.5\text{V}, V_{CC} = \text{MIN}, V_{IN} = V_{IH}$ or $V_{IL}$ per Truth Table	$\mu\text{A}$
$V_{OL}$	Output LOW Voltage	54,74		0.25	0.4	$I_{OL} = 4.0\text{mA}$	V
		74		0.35	0.5	$I_{OL} = 8.0\text{mA}$	
$I_{IH}$	Input HIGH Current Any D, R or W $\bar{E}_R$ or $\bar{E}_W$				20 40	$V_{CC} = \text{MAX}, V_{IN} = 2.7\text{V}$	$\mu\text{A}$
	Any D, R or W $\bar{E}_R$ or $\bar{E}_W$				0.1 0.2	$V_{CC} = \text{MAX}, V_{IN} = 7.0\text{V}$	mA
$I_{IL}$	Input LOW Current Any D, R, or W $\bar{E}_R$ or $\bar{E}_W$				-0.4 -0.8	$V_{CC} = \text{MAX}, V_{IN} = 0.4\text{V}$	mA
$I_{CC}$	Power Supply Current (Note 2)			25	40	$V_{CC} = \text{MAX}$	mA

## AC CHARACTERISTICS: $T_A = 25^\circ\text{C}$

Symbol	Parameter	Limits			Test Conditions	Units
		Min.	Typ.	Max.		
$t_{PLH}$ $t_{PHL}$	Propagation Delay, Negative-Going $\bar{E}_R$ to Outputs		20 20	30 30	Fig. 1	$V_{CC} = 5.0\text{V}$ $C_L = 15\text{pF}$ $R_L = 2\text{k}\Omega$
$t_{PLH}$ $t_{PHL}$	Propagation Delay, $R_A$ or $R_B$ to Q Outputs		25 24	40 40	Fig. 2	
$t_{PLH}$ $t_{PHL}$	Propagation Delay, Negative-Going $\bar{E}_W$ to Q Outputs		30 26	40 40	Fig. 1	
$t_{PLH}$ $t_{PHL}$	Propagation Delay, Data Inputs to Q Outputs		30 22	45 35	Fig. 1	

### Notes:

- 1) Conditions for testing, not shown in the Table, are chosen to guarantee operation under "worst case" conditions.
- 2)  $I_{CC}$  is measured under the following worst-case conditions: 4.5V is applied to all data inputs and both enable inputs, all address inputs are grounded, and all outputs are open.
- 3) Typical values are at  $V_{CC} = 5.0\text{V}$ ,  $T_A = 25^\circ\text{C}$



## AC SET-UP REQUIREMENTS: $T_A = 25^\circ\text{C}$

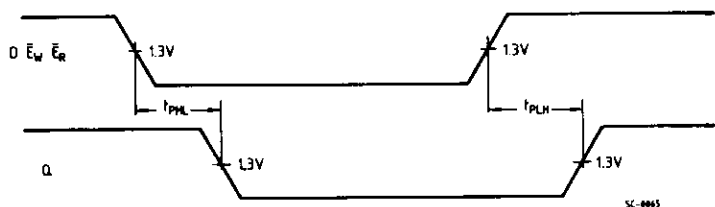
Symbol	Parameter	Limits			Test Conditions	Units
		Min.	Typ.	Max.		
$t_W$	Clock Pulse Width (LOW) for $\bar{E}_W$	25			$V_{CC} = 5.0\text{V}$ Fig. 3	ns
$t_{SD}$ (Note 3)	Set-up Time, Data Inputs with Respect to Positive-Going $\bar{E}_W$	10				ns
$t_{HD}$	Hold Time, Data Inputs with Respect to Positive-Going $\bar{E}_W$	15				ns
$t_{SW}$ (Note 5)	Set-up Time, Write Select Inputs $W_A$ and $W_B$ with Respect to Negative-Going $\bar{E}_W$	15				ns
$t_{HW}$	Hold Time, Write Select Inputs $W_A$ and $W_B$ with Respect to Negative-Going $\bar{E}_W$	15				ns
$t_{LATCH}$	Latch Time	25				ns

### Notes:

- 3) The Data to Enable Set-up Time is defined as the time required for the logic level to be present at the Data input prior to the enable transition for LOW to HIGH in order for the latch to recognize and store the new data.
- 4) The Hold Time ( $t_h$ ) is defined as the minimum time following the enable transition from LOW to HIGH that the logic level must be maintained at the input in order to ensure continued recognition.
- 5) The address to Enable Set-up Time is the time before the HIGH to LOW Enable transition the Address must be stable so that the correct latch is addressed and the other latches are not affected.
- 6) The shaded areas indicate when the inputs are permitted to change for predictable output performance.

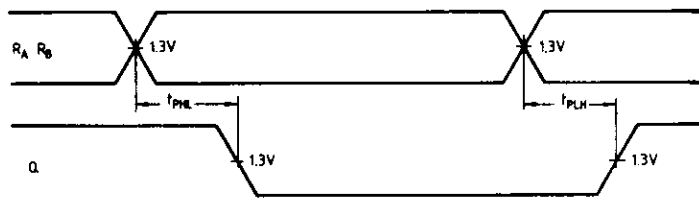
## AC WAVEFORMS

Fig. 1



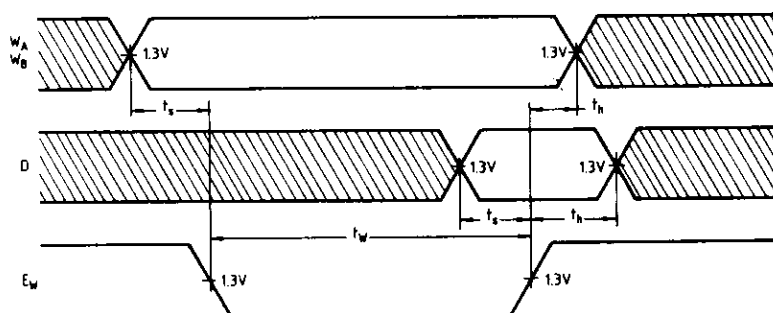
SC-0005

Fig. 2



SC-0006

Fig. 3



SC-0007